

Search Notes**Application/Control No.**

10/699,157

Examiner

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Applicant(s)/Patent under Reexamination

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Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	706	10/28/2005	KCC
	710		
	714		
	712		
	723		
438	725		
438	637		
438	638	10/28/05	KCC

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Keywords search USPTO, USPTO-pub. EPO, JPO, Derwent IBM-TDB, inventer search	10/28/2005	KCC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner